## ${ }^{12}$ C, Nonvolatile Memory, Quad 64/256Position Digital potentiometers

## Preliminary Technical Data

## FEATURES

AD5253: Quad 64-Position Resolution
AD5254: Quad 256-Position Resolution
Nonvolatile Memory ${ }^{1}$ Maintains Wiper Settings
Resistance Tolerance Stored In Nonvolatile Memory
$1 \mathrm{k} \Omega, 10 \mathrm{k} \Omega, 50 \mathrm{k} \Omega 100 \mathrm{k} \Omega$
I2C Compatible Serial Interface
Wiper Settings Read Back
Linear Increment/Decrement Predefined Instructions
+/-6dB Log taper Increment/Decrement Predefined Instructions
Single Supply 2.7 V to 5.5 V
Dual Supply $\pm 2.7 \mathrm{~V}$
Logic Operation Voltage 2.7V to 5V
Power On Presets to EEMEM Settings with Refresh Time $<1 \mathrm{~ms}$ Nonvolatile Memory Write Protection
100 -Year Typical Data Retention $\mathrm{T}_{\mathrm{A}}=55^{\circ} \mathrm{C}$
Operating Temperature $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
TSSOP-20

## APPLICATIONS

Mechanical Potentiometer Replacement
Low Resolution DAC Replacement
Sensors Calibrations
Electronics Level Settings
RF Base Station Power Amp Bias Control
Programmable Gain and Offset Control
Programmable Attentuator
Programmable Voltage to Current Conversion
Programmable Power Supply
Programmable Filters
Line Impedance Matching

## GENERAL DESCRIPTION

The AD5253/AD5254 is a dual channel, digitally controlled variable resistor (VR) with resolutions of 1024 positions. This device performs the same electronic adjustment function as a potentiometer or variable resistor. The AD5253/AD5254's versatile programming via a Micro Controller allows multiple modes of operation and adjustment.
In the direct program mode a predetermined setting of the RDAC register can be loaded directly from the micro controller. Another key mode of operation allows the RDAC register to be refreshed with the setting previously stored in the EEMEM register. When changes are made to the RDAC register to establish a new wiper position, the value of the setting can be saved into the EEMEM by executing an EEMEM save operation. Once the settings are saved in the EEMEM register, these values will be transferred automatically to the RDAC register to set the wiper position at system power ON. Such operation is enabled by the internal preset strobe and the preset can also be accessed externally.
The basic mode of adjustment is the increment and decrement from the present setting of the Wiper position setting (RDAC) register. An internal scratch pad RDAC register can be moved UP or REV PrB 5/6/2003
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DOWN, one step of the nominal resistance between terminals A-and-B. This linearly changes the wiper-to-B terminal resistance ( $\mathrm{R}_{\mathrm{WB}}$ ) by one out of 64/256 positions of the AD5253/AD5254 end-to-end resistance ( $\mathrm{R}_{\mathrm{AB}}$ ). For non-linear changes in wiper setting, a left/right shift command adjusts levels in 6 dB steps which can be useful for sound and light alarm applications.
The AD5253/AD5254 is available in the thin TSSOP-20 package. All parts are guaranteed to operate over the extended industrial temperature range of $-40^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$.

## FUNCTIONAL BLOCK DIAGRAMS



## Notes

1: The terms Nonvolatile Memory and EEMEM are used interchangeably.
2: The terms digital potentiometer, VR, and RDAC are used interchangeably.

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## PRELIMINARY TECHNICAL DATA

Nonvolatile Memory Digital Potentiometers
ELECTRICAL CHARACTERISTICS 1k, 10k, 50k, 100k $\Omega$ VERSIONS ${\left(V_{00}=+3 V \pm 10 \% ~ o r ~\right.}^{2}+5 \mathrm{~V} \pm 10 \%$ and $\mathrm{V}_{\mathrm{SS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{A}}=+\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{B}}=0 \mathrm{~V},-40^{\circ} \mathrm{C}<\mathrm{T}_{\mathrm{A}}<+125^{\circ} \mathrm{C}$ unless otherwise noted.)

| Parameter | Symbol | Conditions | Min | Typ ${ }^{1}$ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| DC CHARACTERISTICS RHEOSTAT MODE <br> Resistor Differential NL ${ }^{2}$ <br> Resistor Nonlinearity ${ }^{2}$ <br> Nominal resistor tolerance <br> Resistance Temperature Coefficent <br> Wiper Resistance <br> Wiper Resistance | $\begin{aligned} & \text { Specificati } \\ & \left\lvert\, \begin{array}{l} \mathrm{R}-\mathrm{DNL} \\ \mathrm{R}-\mathrm{INL} \\ \Delta \mathrm{R} \\ \mathrm{R}_{\mathrm{AB}} / \Delta \mathrm{T} \\ \mathrm{R}_{\mathrm{W}} \\ \mathrm{R}_{\mathrm{W}} \end{array}\right. \end{aligned}$ | apply to all VRs | $\begin{gathered} -1 \\ -2 \\ -30 \end{gathered}$ | $\begin{gathered} \pm 1 / 4 \\ \pm 1 / 2 \\ X \\ X 0 \\ 200 \end{gathered}$ | $\begin{aligned} & +1 \\ & +2 \\ & 30 \\ & 100 \end{aligned}$ | $\begin{array}{r} \text { LSB } \\ \mathrm{LSB} \\ \% \\ \mathrm{ppm} /{ }^{\circ} \mathrm{C} \\ \Omega \\ \Omega \end{array}$ |
| DC CHARACTERISTICS POTENTIOMETER <br> Resolution <br> Integral Nonlinearity ${ }^{3}$ <br> Differential Nonlinearity ${ }^{3}$ <br> Voltage Divider Temperature Coefficent <br> Full-Scale Error <br> Zero-Scale Error | DIVIDER M <br> N <br> INL <br> DNL <br> $\Delta \mathrm{V}_{\mathrm{W}} / \Delta \mathrm{T}$ <br> $V_{\text {WFSE }}$ <br> $V_{\text {WZSE }}$ | Specifications apply to all VRs <br> AD5253/AD5254 <br> Code $=$ Half-scale <br> Code = Full-scale <br> Code = Zero-scale | $\begin{gathered} -2 \\ -1 \\ -3 \\ 0 \end{gathered}$ | $\begin{gathered} \pm 1 / 2 \\ \pm 1 / 4 \\ X \\ -1 \\ +1 \end{gathered}$ | $\begin{aligned} & 6 / 8 \\ & +2 \\ & +1 \\ & +0 \\ & +3 \end{aligned}$ | $\begin{array}{r} \text { Bits } \\ \text { LSB } \\ \text { LSB } \\ \mathrm{ppm} /{ }^{\circ} \mathrm{C} \\ \mathrm{LSB} \\ \mathrm{LSB} \end{array}$ |
| RESISTOR TERMINALS <br> Voltage Range ${ }^{4}$ <br> Capacitance ${ }^{5} \mathrm{Ax}, \mathrm{Bx}$ <br> Capacitance ${ }^{5}$ Wx <br> Common-mode Leakage Current ${ }^{7}$ | $\begin{aligned} & V_{A, B, W} \\ & C_{A, B} \\ & C_{W} \\ & I_{C M} \end{aligned}$ | $\begin{aligned} & f=1 \mathrm{MHz} \text {, measured to } G N D, \text { Code }=\text { Half-scale } \\ & f=1 \mathrm{MHz} \text {, measured to } G N D, \text { Code }=\text { Half-scale } \\ & V_{A}=V_{B}=V_{D D} / 2 \end{aligned}$ | Vss | $\begin{gathered} 45 \\ 60 \\ 0.01 \end{gathered}$ | $V_{D D}$ $1$ | V pF pF $\mu \mathrm{A}$ |
| DIGITAL INPUTS \& OUTPUTS <br> Input Logic High <br> Input Logic Low <br> Output Logic High <br> Output Logic High <br> Output Logic Low <br> Input Current <br> Input Capacitance ${ }^{5}$ | $\mathrm{V}_{\mathrm{IH}}$ <br> $V_{\text {IL }}$ <br> $\mathrm{V}_{\mathrm{OH}}$ <br> $\mathrm{V}_{\mathrm{OH}}$ <br> $\mathrm{V}_{\mathrm{OL}}$ <br> IIL <br> $\mathrm{C}_{\mathrm{IL}}$ | with respect to GND <br> with respect to GND $\begin{aligned} & R_{\text {PUIL-UP }}=2.2 \mathrm{~K} \Omega \text { to }+5 \mathrm{~V} \\ & \mathrm{I}_{\mathrm{OH}}=40 \mu \mathrm{~A}, \mathrm{~V}_{\text {LOGIC }}=+5 \mathrm{~V} \\ & \mathrm{I}_{\mathrm{OL}}=1.6 \mathrm{~mA}, \mathrm{~V}_{\text {LOGIC }}=+5 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{IN}}=0 \mathrm{~V} \text { or } \mathrm{V}_{\mathrm{DD}} \end{aligned}$ | $\begin{gathered} 0.3 \cdot V_{D D} \\ \\ 4.9 \\ 4 \end{gathered}$ | 5 | $\begin{gathered} 0.7 \cdot V_{D D} \\ \\ 0.4 \\ \pm 1 \end{gathered}$ | V $V$ $V$ $V$ $V$ $\mu A$ pF |
| POWER SUPPLIES <br> Single-Supply Power Range <br> Dual-Supply Power Range <br> Positive Supply Current <br> Programming Mode Current <br> Read Mode Current <br> Negative Supply Current <br> Power Dissipation ${ }^{6}$ <br> Power Supply Sensitivity | $V_{D D}$ <br> $V_{D D} / V_{S S}$ <br> $I_{D D}$ <br> $I_{D(P G)}$ <br> $I_{D(\text { READ })}$ <br> $\mathrm{I}_{\mathrm{SS}}$ <br> $P_{\text {DISS }}$ <br> PSS | $\begin{aligned} & V_{S S}=0 \mathrm{~V} \\ & V_{S S}=0 \mathrm{~V} \\ & V_{I H}=V_{D D} \text { or } V_{I L}=G N D \\ & V_{I H}=V_{D D} \text { or } V_{I L}=G N D \\ & V_{I H}=V_{D D} \text { or } V_{I L}=G N D \\ & V_{I H}=V_{D D} \text { or } V_{I L}=G N D, V_{D D}=2.5 \mathrm{~V}, V_{S S}=-2.5 \mathrm{~V} \\ & V_{I H}=V_{D D} \text { or } V_{I L}=G N D \\ & \Delta V_{D D}=+5 \mathrm{~V} \pm 10 \% \end{aligned}$ | $\begin{gathered} 2.7 \\ \pm 2.2 \end{gathered}$ | $\begin{gathered} 2 \\ 15 \\ 650 \\ \\ 0.002 \end{gathered}$ | $\begin{gathered} 5.5 \\ \pm 2.7 \\ 10 \\ \\ 10 \\ 0.05 \\ 0.01 \end{gathered}$ | V V $\mu \mathrm{A}$ mA $\mu \mathrm{A}$ $\mu \mathrm{A}$ mW $\% / \%$ |
| DYNAMIC CHARACTERISTICS ${ }^{5,7}$ <br> Bandwidth - 3dB <br> Total Harmonic Distortion <br> $V_{W}$ Settling Time <br> Resistor Noise Voltage <br> Crosstalk | BW <br> THD w $t_{s}$ <br> $\mathrm{e}_{\text {N_WB }}$ <br> $\mathrm{C}_{\mathrm{T}}$ | $\begin{aligned} & R_{A B}=1 \mathrm{k} / 10 \mathrm{k} / 50 \mathrm{k} / 100 \mathrm{k} \Omega \\ & V_{A}=1 \mathrm{Vrms}, \mathrm{~V}_{B}=0 \mathrm{~V}, \mathrm{f}=1 \mathrm{KHz} \\ & \mathrm{~V}_{\mathrm{A}}=\mathrm{VDD}, \mathrm{~V}_{B}=0 \mathrm{~V}, 50 \% \text { of final value } \end{aligned}$ <br> 1k/10k/50k/100k $R_{W B}=5 \mathrm{~K} \Omega, f=1 \mathrm{KHz}$ <br> $V_{A}=V_{D D}, V_{B}=0 V$, Measue $V_{W}$ with adjacent <br> VR making full scale change |  | $\begin{gathered} \text { TBD } \\ 0.003 \\ \\ \text { TBD } \\ 9 \\ \\ -65 \end{gathered}$ |  | $\begin{array}{r} \mathrm{kHz} \\ \% \\ \\ \begin{array}{r} \mu \mathrm{s} \\ \mathrm{nV} \sqrt{\mathrm{~Hz}} \end{array} \\ \mathrm{~dB} \end{array}$ |

## PRELIMINARY TECHNICAL DATA

ELECTRICAL CHARACTERISTICS 1k, 10k, 50k, 100k $\Omega$ VERSIONS $\left(V_{D D}=+3 V \pm 10 \%\right.$ to $+5 \mathrm{~V} \pm 10 \%$ and
$\mathrm{V}_{\mathrm{SS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{A}}=+\mathrm{V}_{\mathrm{DD}}, \mathrm{V}_{\mathrm{B}}=0 \mathrm{~V},-40^{\circ} \mathrm{C}<\mathrm{T}_{\mathrm{A}}<+125^{\circ} \mathrm{C}$ unless otherwise noted.)

| Parameter | Symbol | Conditions | Min | Typ ${ }^{1}$ | Max | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| INTERFACE TIMING CHARACTERISTICS applies to all parts(Notes 5,8) |  |  |  |  |  |  |
| SCL Clock Frequency | $\mathrm{f}_{\text {SCL }}$ |  | 0 |  | 400 | kHz |
| $\mathrm{t}_{\text {BUF }}$ Bus free time between STOP \& START | $\mathrm{t}_{1}$ |  | 1.3 |  |  | $\mu \mathrm{s}$ |
| $\mathrm{t}_{\text {HD; }}$ STA Hold Time (repeated START) | $\mathrm{t}_{2}$ | After this period the first clock pulse is generated | 0.6 |  |  | $\mu \mathrm{s}$ |
| t Low Low Period of SCL Clock | $\mathrm{t}_{3}$ |  | 1.3 |  |  | $\mu \mathrm{s}$ |
| $t_{\text {HIGH }}$ High Period of SCL Clock | $\mathrm{t}_{4}$ |  | 0.6 |  |  | $\mu \mathrm{s}$ |
| $\mathrm{t}_{\text {Su; }}$ Sta Setup Time For START Condition | t5 |  | 0.6 |  |  | $\mu \mathrm{s}$ |
| $\mathrm{t}_{\text {HD; DAT }}$ Data Hold Time | $\mathrm{t}_{6}$ |  | 0 |  | 0.9 | $\mu \mathrm{s}$ |
| $t_{\text {SU;DAT }}$ Data Setup Time | $\mathrm{t}_{7}$ |  | 100 |  |  | ns |
| $t_{F}$ Fall Time of both SDA \& SCL signals | $\mathrm{t}_{8}$ |  |  |  | 300 | ns |
| $t_{R}$ Rise Time of both SDA \& SCL signals | t9 |  |  |  | 300 | ns |
| $\mathrm{t}_{\text {SU;STO }}$ Setup time for STOP Condition | t10 |  | 0.6 |  |  | $\mu \mathrm{s}$ |
| Store to Nonvolatile EEMEM Save Time ${ }^{9}$ | $\mathrm{t}_{12}$ | Applies to Command ${ }^{\text {H }}$, $3^{H}$ |  |  | 25 | ms |
| RDY Rise to CS Fall | $\mathrm{t}_{15}$ |  |  |  |  | ns |
| Preset Pulse Width | tPR |  | 50 |  |  | ns |

NOTES:

1. Typicals represent average readings at $+25^{\circ} \mathrm{C}$ and $\mathrm{V}_{D D}=+5 \mathrm{~V}$.
2. Resistor position nonlinearity error $\mathrm{R}-\mathrm{INL}$ is the deviation from an ideal value measured between the maximum resistance and the minimum resistance wiper positions. R -DNL measures the relative step change from ideal between successive tap positions. Parts are guaranteed monotonic. See figure 20 test circuit. $I_{W}=V_{D D} / R$ for both $V_{D D}=+3 \mathrm{~V}$ or $V_{D D}=+5 \mathrm{~V}$.
3. $I N L$ and $D N L$ are measured at $V_{W}$ with the RDAC configured as a potentiometer divider similar to a voltage output $D / A$ converter. $V_{A}=V_{D D}$ and $V_{B}=0 V$

DNL specification limits of $\pm 1$ LSB maximum are Guaranteed Monotonic operating conditions. See Figure 19 test circuit.
4 Resistor terminals $A, B, W$ have no limitations on polarity with respect to each other.
5. Guaranteed by design and not subject to production test.
6. PoIss is calculated from ( $l_{D D} \times V_{D D}=+5 \mathrm{~V}$ ).
7. All dynamic characteristics use $V_{D D}=+5 \mathrm{~V}$.
8. See timing diagram for location of measured values. All input control voltages are specified with $\mathrm{t}_{\mathrm{R}}=\mathrm{t}_{\mathrm{F}}=2.5 \mathrm{~ns}(10 \%$ to $90 \%$ of 3 V$)$ and timed from a voltage level of 1.5 V . Switching characteristics are measured using both $\mathrm{V}_{\mathrm{DD}}=+3 \mathrm{~V}$ or +5 V .
9. Low only for commands $8,9,10,2,3$ : CMD_8 ~ 1ms; CMD_9,10 ~0.1ms; CMD_2,3 ~20ms

## PRELIMINARY TECHNICAL DATA

## Nonvolatile Memory Digital Potentiometers

Timing Diagram


Figure 1. Timing Diagram
Data of AD5253/AD5254 is accepted from the $\mathrm{I}^{2} \mathrm{C}$ bus in the following serial format:

| S | 0 | 1 | 0 | 1 | 1 | A | A | R/ | A | I7 | I6 | I5 | I4 | I3 | I2 | I1 | I0 | A | D | D | D | D | D | D | D | D | A | P |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- | :--- |

Where:
$\mathbf{S}=$ Start Condition
$\mathbf{P}=$ Stop Condition
$\mathbf{A}=$ Acknowledge
X = Don't Care

ADD1, ADD0 $=$ Package pin programmable address bits $\mathbf{R} / \overline{\mathrm{W}}=$ Read Enable at High and Write Enable at Low
I7-10 = Instruction bits
D5-D0 $=6$ Data Bits. D7 and D6 $=\mathrm{X}($ AD5253 $)$
D7- D0 = 8 Data Bits (AD5254)


Figure 2.Complete Serial Transmission

## PRELIMINARY TECHNICAL DATA

## Nonvolatile Memory Digital Potentiometers

Absolute Maximum Rating $\left(\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}\right.$, unless otherwise noted)
$V_{\text {DD }}$ to GND $-0.3,+7 \mathrm{~V}$
$V_{\text {SS }}$ to GND $+0.3,-7 \mathrm{~V}$

$\mathrm{V}_{\mathrm{A}}, \mathrm{V}_{\mathrm{B}}, \mathrm{V}_{\mathrm{W}}$ to GND................................................ $\mathrm{V}_{\mathrm{SS}}, \mathrm{V}_{\mathrm{DD}}$
$\mathrm{A}_{\mathrm{X}}-\mathrm{B}_{\mathrm{X}}, \mathrm{A}_{\mathrm{X}}-\mathrm{W}_{\mathrm{X}}, \mathrm{B}_{\mathrm{X}}-\mathrm{W}_{\mathrm{X}}$
Pulse $\pm 20 \mathrm{~mA}$
Continuous $\pm 5 \mathrm{~mA}$
Digital Inputs \& Output Voltage to GND................... $0 \mathrm{~V},+7 \mathrm{~V}$
Operating Temperature Range......................... $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
Maximum Junction Temperature ( $\mathrm{T}_{\mathrm{J}}$ MAX). $\qquad$ $+150^{\circ} \mathrm{C}$
Storage Temperature $-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$ Lead Temperature (Soldering, 10 sec ) $\qquad$ $+300^{\circ} \mathrm{C}$ Thermal Resistance $\theta_{\mathrm{JA}}$,

TSSOP-20 $\qquad$ $\mathrm{XXX}^{\circ} \mathrm{C} / \mathrm{W}$
Package Power Dissipation $=\left(\mathrm{T}_{\mathrm{J}} \mathrm{MAX}-\mathrm{T}_{\mathrm{A}}\right) / \theta_{\mathrm{JA}}$

## Ordering Guide

| Model AD5253BRU1 | Step 64 | $\mathrm{R}_{\mathrm{AB}}$ <br> (k $\Omega$ ) <br> 1 | Temp Range ( ${ }^{\circ} \mathrm{C}$ ) $-40 /+125$ | Package Descripti on TSSOP20 | Package Option RU-20 |
| :---: | :---: | :---: | :---: | :---: | :---: |
| AD5253BRU10 | 64 | 10 | -40/+125 | $\begin{aligned} & \text { TSSOP- } \\ & 20 \\ & \hline \end{aligned}$ | RU-20 |
| AD5253BRU50 | 64 | 50 | -40/+125 | $\begin{aligned} & \text { TSSOP- } \\ & 20 \\ & \hline \end{aligned}$ | RU-20 |
| AD5253BRU100 | 64 | 100 | -40/+125 | $\begin{aligned} & \text { TSSOP- } \\ & 20 \\ & \hline \end{aligned}$ | RU-20 |
| AD5254BRU1 | 256 | 1 | -40/+125 | $\begin{aligned} & \hline \text { TSSOP- } \\ & 20 \\ & \hline \end{aligned}$ | RU-20 |
| AD5254BRU10 | 256 | 10 | -40/+125 | $\begin{aligned} & \text { TSSOP- } \\ & 20 \\ & \hline \end{aligned}$ | RU-20 |
| AD5254BRU50 | 256 | 50 | -40/+125 | $\begin{aligned} & \text { TSSOP- } \\ & 20 \\ & \hline \end{aligned}$ | RU-20 |
| AD5254BRU100 | 256 | 100 | -40/+125 | $\begin{aligned} & \text { TSSOP- } \\ & 20 \end{aligned}$ | RU-20 |

The AD5253/AD5254 contain x,xxx transistors.
Die size: $x^{\prime}$ mil $x$ y' mil, $z^{\prime}$ sq. mil

AD5253/AD5254 PIN CONFIGURATION


AD5253/AD5254 PIN FUNCTION DESCRIPTION

| \# | Name | Description |
| :---: | :---: | :---: |
| 1 | W0 | Wiper terminal of RDAC0. |
| 2 | B0 | B terminal of RDAC0 |
| 3 | A0 | A terminal of RDAC0. |
| 4 | ADD0 | I2C Device Address 0 |
| 5 | $\overline{\mathrm{WP}}$ | Write Protect, Active Low |
| 6 | W1 | Wiper terminal of RDAC1 |
| 7 | B1 | B terminal of RDAC1 |
| 8 | A1 | A terminal of RDAC1. |
| 9 | SDA | Serial Data Input Pin. Shifts in one bit at a time on positive clock CLK edges. MSB loaded first. |
| 10 | $\mathrm{V}_{\text {SS }}$ | Negative Supply. Connect to zero volt for single supply |
| 11 | A2 | A terminal of RDAC2. |
| 12 | B2 | B terminal of RDAC2. |
| 13 | W2 | Wiper terminal of RDAC2 |
| 14 | SCL | Serial Input Register clock pin. Shifts in one bit at a time on positive clock edges. |
| 15 | DGND | Digital Ground. Connect to System Analog Ground at a Single Point |
| 16 | ADD1 | I2C Device Address 1 |
| 17 | A3 | A terminal of RDAC3 |
| 18 | B3 | Wiper terminal of RDAC3 |
| 19 | W3 | W terminal of RDAC3 |
| 20 | $\mathrm{V}_{\mathrm{DD}}$ | Positive Power Supply Pin. |

## PRELIMINARY TECHNICAL DATA

## Nonvolatile Memory Digital Potentiometers

## OPERATIONAL OVERVIEW

The AD5253/AD5254 digital potentiometer is designed to operate as a true variable resistor replacement device for analog signals that remain within the terminal voltage range of $\mathrm{V}_{\mathrm{SS}}<\mathrm{V}_{\text {TERM }}<\mathrm{V}_{\mathrm{DD}}$. The basic voltage range is limited to a $\mathrm{V}_{\mathrm{DD}}-$ $\mathrm{V}_{\mathrm{SS}}<5.5 \mathrm{~V}$. Control of the digital potentiometer allows both scratch pad register (RDAC register) changes to be made, as well as 100,000 times of nonvolatile electrically erasable memory (EEMEM) register operations. The EEMEM update process takes approximately 20.2 ms , during this time the shift register is locked preventing any changes from taking place. The EEMEM retention is designed to last 10 years without refresh. The scratch pad register can be changed incrementally by using the software controlled Increment/Decrement instruction or the Shift Left/Right instruction command. Alternately the scratch pad register can be programmed with any position value using the standard $\mathrm{I}^{2} \mathrm{C}$ serial interface mode by loading the representative data word. The scratch pad register can be loaded with the current contents of the nonvolatile EEMEM register under program control. At system power ON, the default value of the scratch pad memory is the value previously saved in the EEMEM register. The factory EEMEM preset values are mid-scale $32 / 128$ for AD5253/AD5254 respectively.
The serial input data register uses a 32 -bit slave address/instruction/data WORD.

## SERIAL DATA INTERFACE

The AD5253/AD5254 employs a two-wire $I^{2} \mathrm{C}$ serial interface requiring only two I/O lines of a standard microprocessor port. Key features of this interface include:

- Read \& Write capability to all registers
- Direct parallel refresh of all RDAC wiper registers from corresponding EEMEM registers
- Increment \& Decrement instructions for each RDAC wiper register
- Left \& right Bit Shift of all RDAC wiper registers to achieve 6dB level changes
- Permanent storage of the present scratch pad RDAC register values into the corresponding EEMEM register
- EEMEM Write Protect

Figure 1 shows the timing diagram for signals on the wire bus. The 2-wire bus can have several devices attached in addition to the AD5253/AD5254. The two bus lines (SDA and SCL) must be high when the bus is not in use. When in use, the port bits are toggled to generate the appropriate signals for SDA and SCL. For $\mathrm{I}^{2} \mathrm{C}$ applications, two pull up resistors are required at both the SDA and SCL pins to VDD.
The AD5253/AD5254 can operate SCL of up to 400 kHz . A master device sends information to the AD5253/AD5254 by transmitting the AD5253/AD5254's address over the bus and then transmitting the desired information. Each transmission consists of a START condition, the AD5253/AD5254's programmable slave address, an instruction byte, 2 data bytes consist of 10 data bits, and a STOP condition.

The address byte, instruction byte, and data bytes are transmitted between the START and STOP conditions. The state of SDA is allowed to change only if SCL is low, with the exceptions at START and STOP conditions. SDA must remain stable and is sampled (read or write depends upon the state of R/W) when SCL is high. Data is transmitted in 8-bit bytes.

## The START and STOP Conditions

When the bus is not in use, both SCL and SDA must be high. A bus master signals the beginning of a transmission with a START condition by transitioning SDA from high to low while SCL is high (Figure 3). When the master has finished communicating with the slave, it issues a STOP condition by transitioning SDA from low to high while SCL is high. The bus is then free for another transmission.


Figure 3.START and STOP Conditions

## The Slave Address

The AD5253/AD5254's slave address is seven bits long (Figure 4). The first five bits (MSBs) of the slave address have been factory programmed to 01011 . The state of the AD5253/AD5254 inputs AD0 and AD1 determine the final two bits of the 7 -bit slave address, These input pins may be connected to VDD or GND, or may be actively driven by TTL or CMOS logic levels. There are four possible addresses for the AD5253/AD5254, and therefore a maximum of four such devices may be on the bus at the same time. The eighth bit (LSB) in the slave address byte is for read write purpose. Active high allows data to be read back from the input register. Active low allows data to be written to the input register. The AD5253/AD5254 watches the bus continuously, waiting for a START condition followed by its slave address. When it recognizes its slave address, it is ready to accept data.


Figure 4. Slave Address and R/W Byte

## The Instruction Byte

(To be determined)

## The Data Bytes

(To be determined)

Table 1. AD5253/AD5254 Instruction/Operation Truth Table

| Slave Address \& R/W ByteB31 ...............................................AD6 AD5 AD4 AD3 AD2 AD1 AD0 R/W |  |  |  |  |  |  |  | Instruction Byte <br> B23 .................................... B16 |  |  |  |  |  |  |  | Data Byte B7 ......... B0 | Operation |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  |  |  |  |  |  | I7 | I6 | I5 | I4 | I3 | I2 | I1 | I0 | D7 ........ D0 |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 0 |  |  |  |  |  |  |  | X .......... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 0 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 0 |  |  |  |  |  |  |  | X .......... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 0 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 0 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 0 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 0 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 0 |  |  |  |  |  |  |  | X .......... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 0 | 1 |  |  |  |  |  |  |  | X ........... X |  |
| 0 | 1 | 0 | 1 | 1 | 0 | 0 | 1 | 1 |  |  |  |  |  |  |  | X .......... X |  |

## NOTES:

1. The RDAC register is a volatile scratch pad register that is refreshed at power ON from the corresponding non-volatile EEMEM register.
2. The increment, decrement and shift commands ignore the contents of the shift register Data Byte.

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## Nonvolatile Memory Digital Potentiometers

Detail Potentiometer Operation
The actual structure of the RDAC is designed to emulate the performance of a mechanical potentiometer. The RDAC contains a string of connected resistor segments, with an array of analog switches that act as the wiper connection to several points along the resistor array. The number of points is the resolution of the device. For example, the AD5253/AD5254 emulates $64 / 256$ connection points with $64 / 256$ equal resistance, $\mathrm{R}_{\mathrm{s}}$, allowing it to provide better than $1.5 \% / 0.4 \%$ set-ability resolution. Figure 5 provides an equivalent diagram of the connections between the three terminals that make up one channel of the RDAC. The switches $\mathrm{SW}_{\mathrm{A}}$ and $\mathrm{SW}_{\mathrm{B}}$ will always be ON while one of the switches $\operatorname{SW}(0)$ to $\operatorname{SW}\left(2^{\mathrm{N}}-1\right)$ will be ON one at a time depends upon the resistance step decoded from the data. The total resistance of the active switches makes up the wiper resistance, $\mathrm{R}_{\mathrm{W}}$.


Figure 5. Equivalent RDAC structure

## PROGRAMMING THE VARIABLE RESISTOR Rheostat Operation

The nominal resistance of the RDAC between terminals A and B are available with values of $1 \mathrm{k} \Omega, 10 \mathrm{k} \Omega, 50 \mathrm{k} \Omega$, and $100 \mathrm{k} \Omega$. The final digits of the part number determine the nominal resistance value, e.g., $1 \mathrm{k} \Omega=1,10 \mathrm{k} \Omega=10,50 \mathrm{k} \Omega=50$, and $100 \mathrm{k} \Omega=100$. The nominal resistance $\left(\mathrm{R}_{\mathrm{AB}}\right)$ of the AD5253/AD5254 VR has 64/256 contact points accessed by the wiper terminal, plus the $B$ terminal contact. The $6 / 8$-bit data word in the RDAC latch is decoded to select one of the $64 / 256$ possible settings. The wiper's first connection starts at the B terminal for data $00_{\mathrm{H}}$. This B-terminal connection has a wiper contact resistance, $\mathrm{R}_{\mathrm{w}}$ of $50 \Omega$, regardless of what the nominal resistance is. The second connection (AD5253 $10 \mathrm{k} \Omega$ part) is the first tap point where $\mathrm{R}_{\mathrm{wB}}=206 \Omega\left[\mathrm{R}_{\mathrm{WB}}=\mathrm{R}_{\mathrm{AB}} / 64+\mathrm{R}_{\mathrm{W}}=\right.$
$156 \Omega+50 \Omega)$ ] for data $01_{\mathrm{H}}$. The third connection is the next tap point representing $\mathrm{R}_{\mathrm{wB}}=312+50=362 \Omega$ for data $02_{\mathrm{H}}$. Each LSB data value increase moves the wiper up the resistor ladder until the last tap point is reached at $\mathrm{R}_{\mathrm{WB}}=9893 \Omega$. See figure 6 for a simplified diagram of the equivalent RDAC circuit.

The general equation, which determines the digitally programmed output resistance between Wx and Bx , is:
$\mathrm{R}_{\mathrm{WB}}(\mathrm{Dx})=\left(\mathrm{Dx} / 2^{\mathrm{N}}\right) * \mathrm{R}_{\mathrm{AB}}+\mathrm{R}_{\mathrm{W}} \quad$ eqn. 1

Where N is the resolution of the $\mathrm{VR}, \mathrm{Dx}$ is the data contained in the RDACx latch, and $R_{A B}$ is the nominal end-to-end resistance. Since $N=6 / 8$-bit and $R_{w}=50 \Omega$ for AD5253/AD5254, eqn. 1 becomes:
$\mathrm{R}_{\mathrm{WB}}(\mathrm{Dx})=(\mathrm{Dx} / 64) * \mathrm{R}_{\mathrm{AB}}+50 \Omega \quad(\mathrm{AD} 5253)$ eqn. 2
$\mathrm{R}_{\mathrm{WB}}(\mathrm{Dx})=(\mathrm{Dx} / 256) * \mathrm{R}_{\mathrm{AB}}+50 \Omega \quad(\mathrm{AD} 5254)$ eqn. 3

For example, when $\mathrm{V}_{\mathrm{B}}=0 \mathrm{~V}$ and A -terminal is open circuit, the following output resistance values will be set by the corresponding RDAC latch codes (applies to AD5253 $\mathrm{R}_{\mathrm{AB}}=10 \mathrm{k} \Omega$ potentiometers):

| Dx <br> $(\mathrm{DEC})$ | $\mathrm{R}_{\mathrm{WB}}$ <br> $(\Omega)$ | Output State |
| :--- | :--- | :--- |
|  |  |  |
| 63 | $9893 \Omega$ | Full-Scale |
| 32 | $5050 \Omega$ | Mid-Scale |
| 1 | $206 \Omega$ | 1 LSB |
| 0 | $50 \Omega$ | Zero-Scale (Wiper contact resistance) |

Note that in the zero-scale condition a finite wiper resistance of $50 \Omega$ is present. Care should be taken to limit the current conduction between W and B in this state to a no more than $\pm 5 \mathrm{~mA}$ continuous or $\pm 20 \mathrm{~mA}$ pulse to avoid degradation or possible destruction of the internal switch contact.


Figure 6. Symmetrical RDAC Operation

## PRELIMINARY TECHNICAL DATA

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Like the mechanical potentiometer the RDAC replaces, the AD5253/AD5254 part is totally symmetrical. The resistance between the wiper W and terminal A also produces a digitally controlled resistance $\mathrm{R}_{\mathrm{WA}}$. Figure 6 shows the symmetrical programmability of the various terminal connections. When these terminals are used, the B-terminal should be tied to the wiper. Setting the resistance value for $\mathrm{R}_{\mathrm{WA}}$ starts at a maximum value of resistance and decreases as the data loaded in the latch is increased in value. The general equation for this operation is:
$\mathrm{R}_{\mathrm{WA}}(\mathrm{Dx})=[(64-\mathrm{Dx}) / 64] * \mathrm{R}_{\mathrm{AB}}+50 \Omega \quad(\mathrm{AD} 5253)$ eqn. 4
$\mathrm{R}_{\mathrm{WA}}(\mathrm{Dx})=[(256-\mathrm{Dx}) / 256] * \mathrm{R}_{\mathrm{AB}}+50 \Omega(\mathrm{AD} 5254)$ eqn. 5
For example, when $\mathrm{V}_{\mathrm{A}}=0 \mathrm{~V}$ and B -terminal is tied to the wiper W the following output resistance values will be set by the corresponding RDAC latch codes (applies to AD5253 $\mathrm{R}_{\mathrm{AB}}=10 \mathrm{k} \Omega$ potentiometers):

| Dx <br> $(\mathrm{DEC})$ | $\mathrm{R}_{\text {WA }}$ <br> $(\Omega)$ | Output State |
| :--- | :--- | :--- |
|  |  |  |
| 63 | 206 | Full-Scale |
| 32 | 5050 | Mid-Scale |
| 1 | 9893 | 1 LSB |
| 0 | 10050 | Zero-Scale |

The typical distribution of $\mathrm{R}_{\mathrm{AB}}$ from channel-to-channel matches of less than $\pm 1 \%$ within the same package. On the other hand, device to device matching is process lot dependent such that a maximum of $\pm 30 \%$ variation is possible.

## PROGRAMMING THE POTENTIOMETER DIVIDER Voltage Output Operation

The digital potentiometer easily generates an output voltage proportional to the input voltage applied to a given terminal. For example connecting A-terminal to +5 V and B -terminal to ground produces an output voltage at the wiper which can be any value starting at zero volts up to 1 LSB less than +5 V . Each LSB of voltage is equal to the voltage applied across terminal AB divided by the $2^{\mathrm{N}}$ position resolution of the potentiometer divider. The general equation defining the output voltage with respect to ground for any given input voltage applied to terminals AB is:
$\begin{array}{ll}\mathrm{V}_{\mathrm{W}}(\mathrm{Dx})=(\mathrm{Dx} / 64) * \mathrm{~V}_{\mathrm{AB}}+\mathrm{V}_{\mathrm{B}} & \text { (AD5253) eqn. } 6 \\ \mathrm{~V}_{\mathrm{W}}(\mathrm{Dx})=(\mathrm{Dx} / 256) * \mathrm{~V}_{\mathrm{AB}}+\mathrm{V}_{\mathrm{B}} & \text { (AD5254) eqn. } 7\end{array}$

Operation of the digital potentiometer in the divider mode results in more accurate operation over temperature. Here the output voltage is dependent on the ratio of the internal resistors and not the absolute value. Therefore, the drift reduces to $50 \mathrm{ppm} /{ }^{\circ} \mathrm{C}$.

## ESD PROTECTION CIRCUITS



Figure 7A. Equivalent Digital Input ESD Protection


Figure 7B. Equivalent Digital Output ESD Protection

Figure 7 shows the equivalent ESD protection circuit for digital pins. Figure 8 shows the equivalent analog-terminal protection circuit for the variable resistors.


Figure 8. Equivalent VR-Terminal ESD Protection

## TEST CIRCUITS

Figures 9 to 18 define the test conditions used in the product specification's table.

# PRELIMINARY TECHNICAL DATA <br> Nonvolatile Memory Digital Potentiometers 



Figure 9. Potentiometer Divider Nonlinearity error test circuit (INL, DNL)


Figure 10. Resistor Position Nonlinearity Error (Rheostat Operation; R-INL, R-DNL)


Figure 11. Wiper Resistance test Circuit


Figure 12. Power supply sensitivity test circuit (PSS, PSSR)


Figure 13. Inverting Gain test Circuit


Figure 14. Non-Inverting Gain test circuit


Figure 15. Gain Vs Frequency test circuit


Figure 16. Incremental ON Resistance Test Circuit


Figure 17. Common Mode Leakage current test circuit


Figure 18. Analog Crosstalk Test Circuit

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Dimensions shown in inches and (mm)

